

2.1 Structure and functions of MOSFET

Principle of MOSFET

2.1.1 PN junction

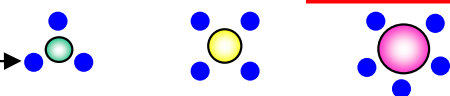
Electrical conductivity control 1

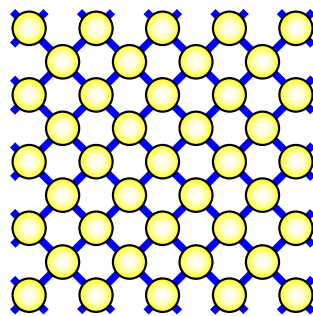
Periodic table

| | III | IV | V | |
|--|-----|----|----|--|
| | B | C | N | |
| | Al | Si | P | |
| | Ga | Ge | As | |
| | In | Sn | Sb | |

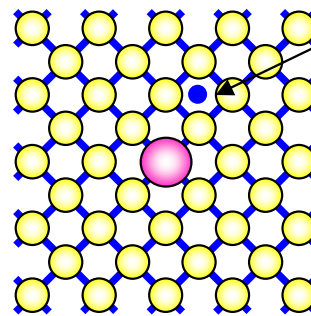
* A free electron (自由電子) is not bound to an atom.

Free Electron (*)

Electron (Blue dot) → 

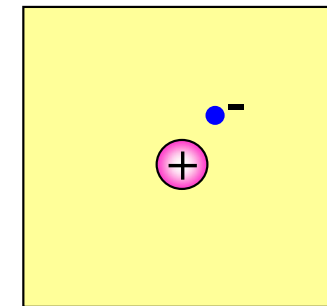


Crystal of Si



P(Phosphorous)-doped Si (*)

* Doping: Introducing an impurity



Simplified sketch

Electrical conductivity control 2

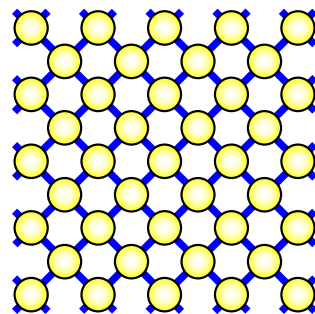
Periodic table

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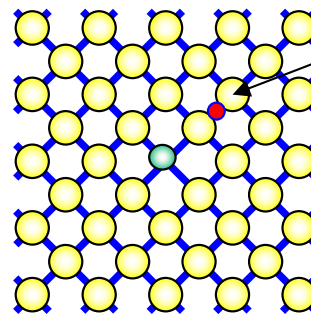
* A hole is an ionized Si atom by transferring a valence electron to an impurity.

Hole (*)

Electron (Blue dot)

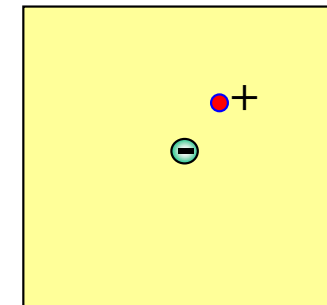


Crystal of Si



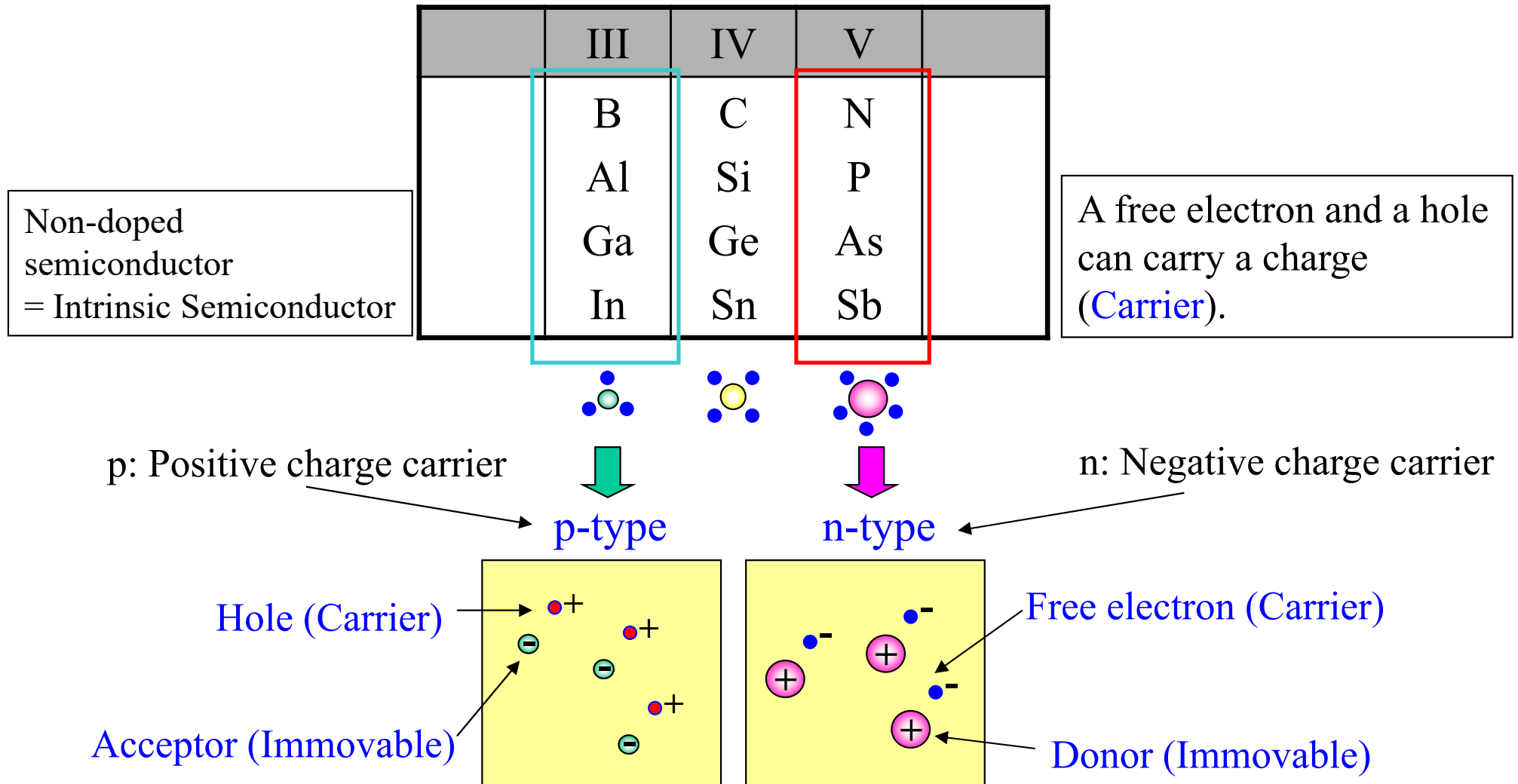
B(Boron)-doped Si (*)

* Doping: Introducing an impurity



Simplified sketch

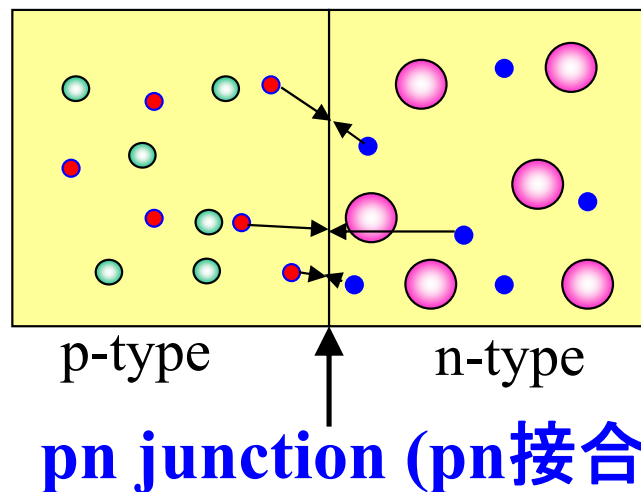
Conductivity type of semiconductor



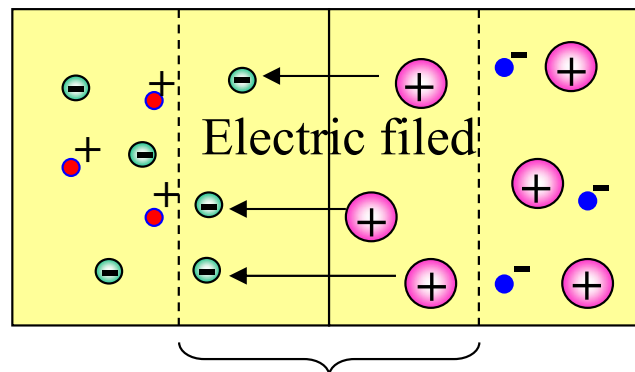
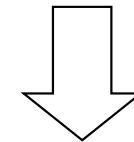
The number of carriers equals to the number of accepters or donors.

Electric field of pn junction

A pn junction is formed at a boundary between the p-type semiconductor and the n-type semiconductor.



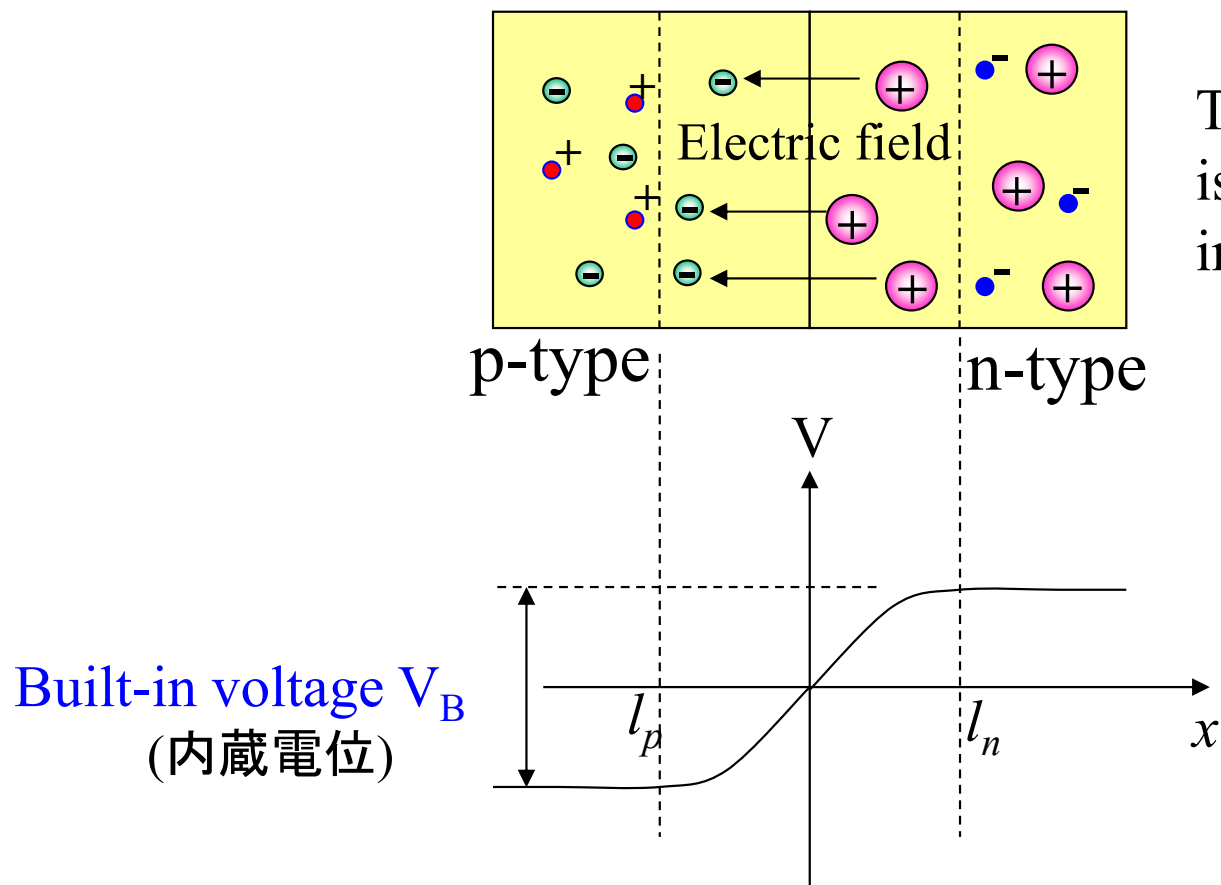
Free electrons and holes are recombined in the vicinity of the pn junction, and a depletion layer of carriers are formed.



The ionized donors and acceptors forms the built-in electric field in the depletion layer.

$$\frac{dE}{dx} = \frac{\rho}{\epsilon_0 \epsilon_{Si}} \quad (\text{Gauss's law})$$

Voltage of pn junction



The built-in voltage V_B is generated by the built-in electric field.

$$E = -\frac{dV}{dx}$$

$$dV = -E \cdot dx$$

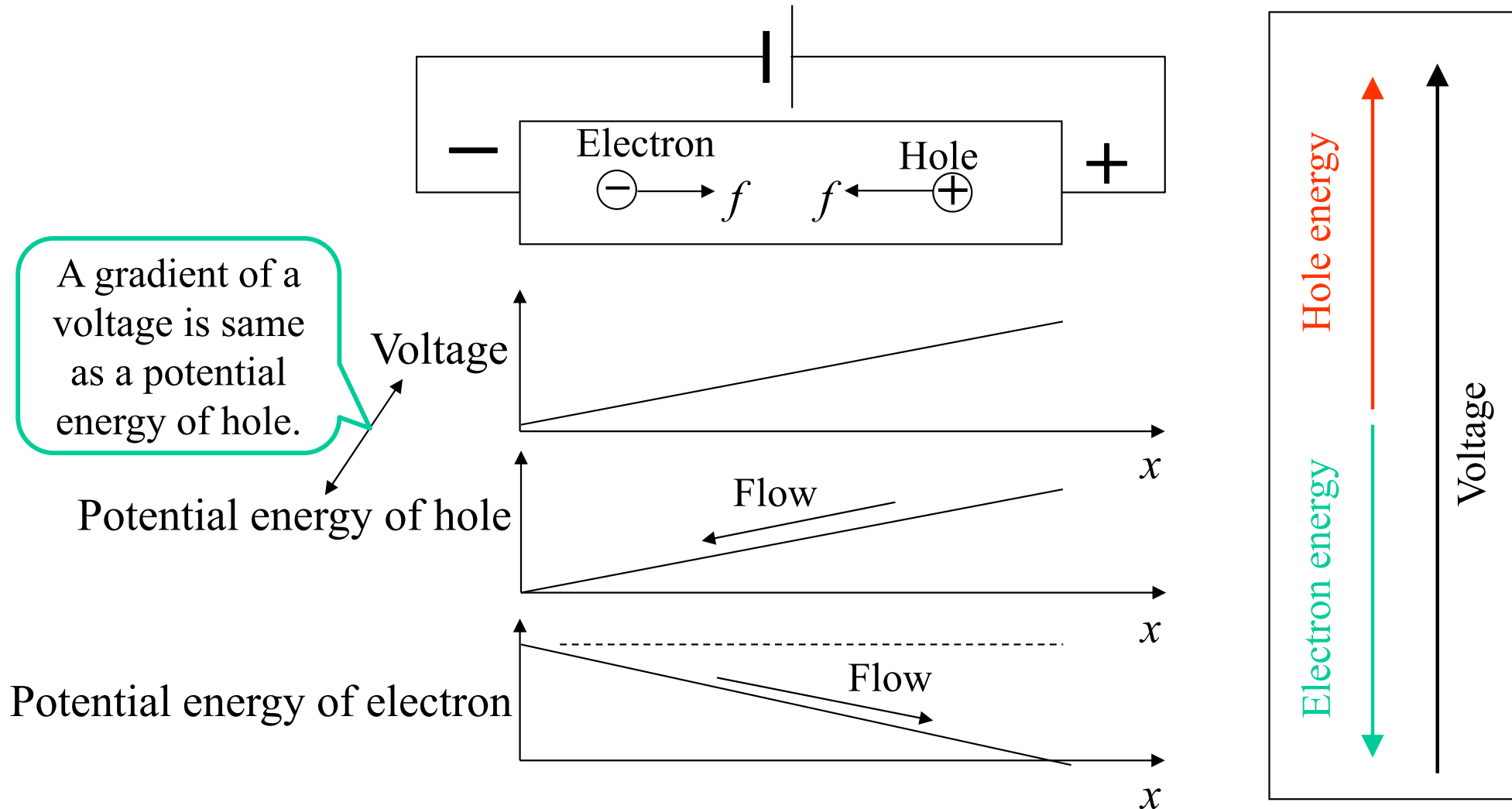
$$V_B = -\int_{l_p}^n E \cdot dx$$

Note: The current does not flow through the pn junction because the electrostatic force and the diffusion of the carrier are balanced in the **equilibrium state**.

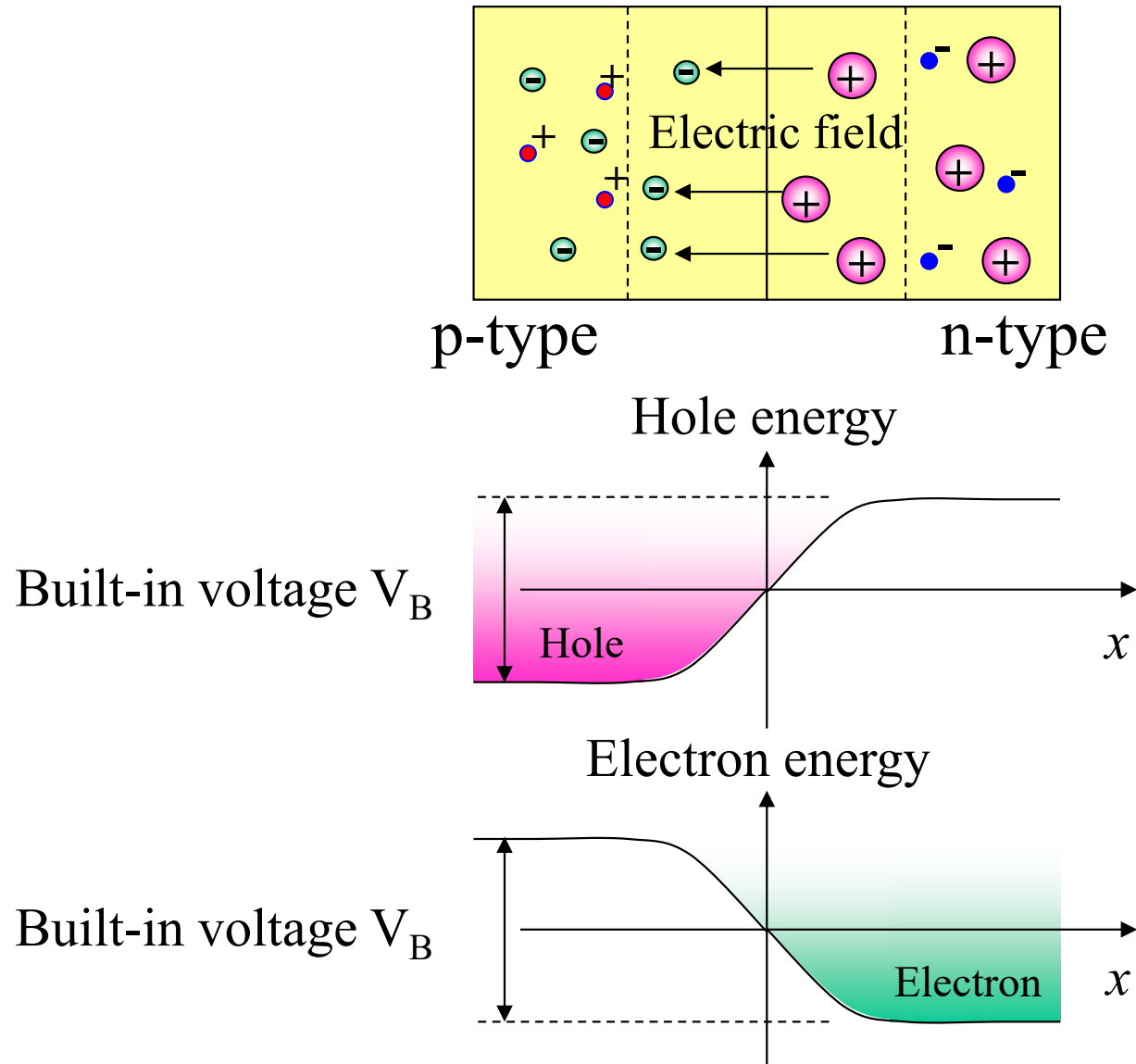
用語解説

- Equilibrium state
 - 平衡状態(熱平衡状態)
 - 外部系とのエネルギーの授受が無い状態
- Steady state
 - 定常状態
 - 時間的变化が無い状態(交流振幅や周波数に変化しない状態も含む)
- Transient state
 - 過渡状態
 - 時間的变化がある状態

Potential energy of electron and hole

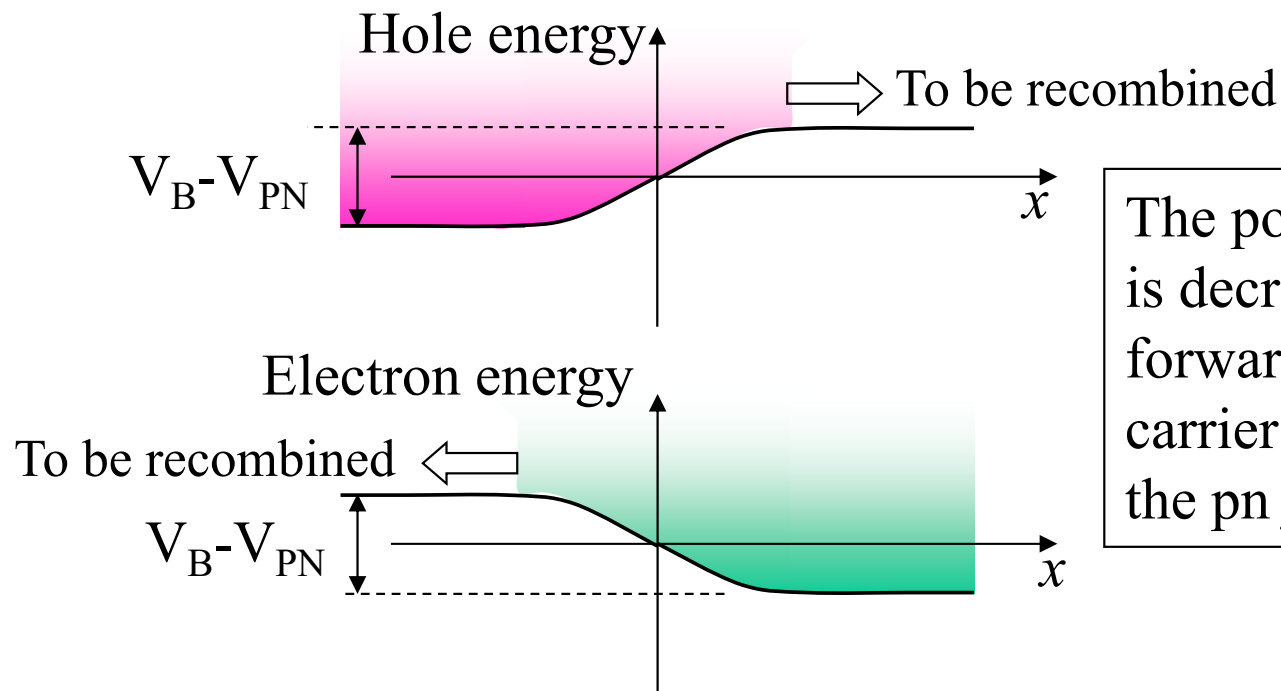
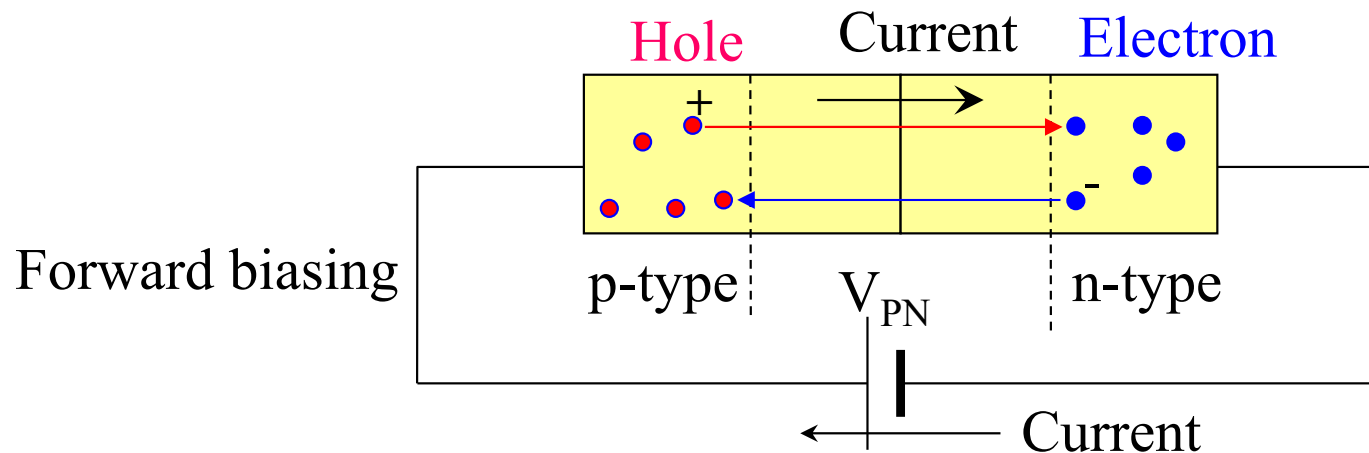


Distribution of carriers



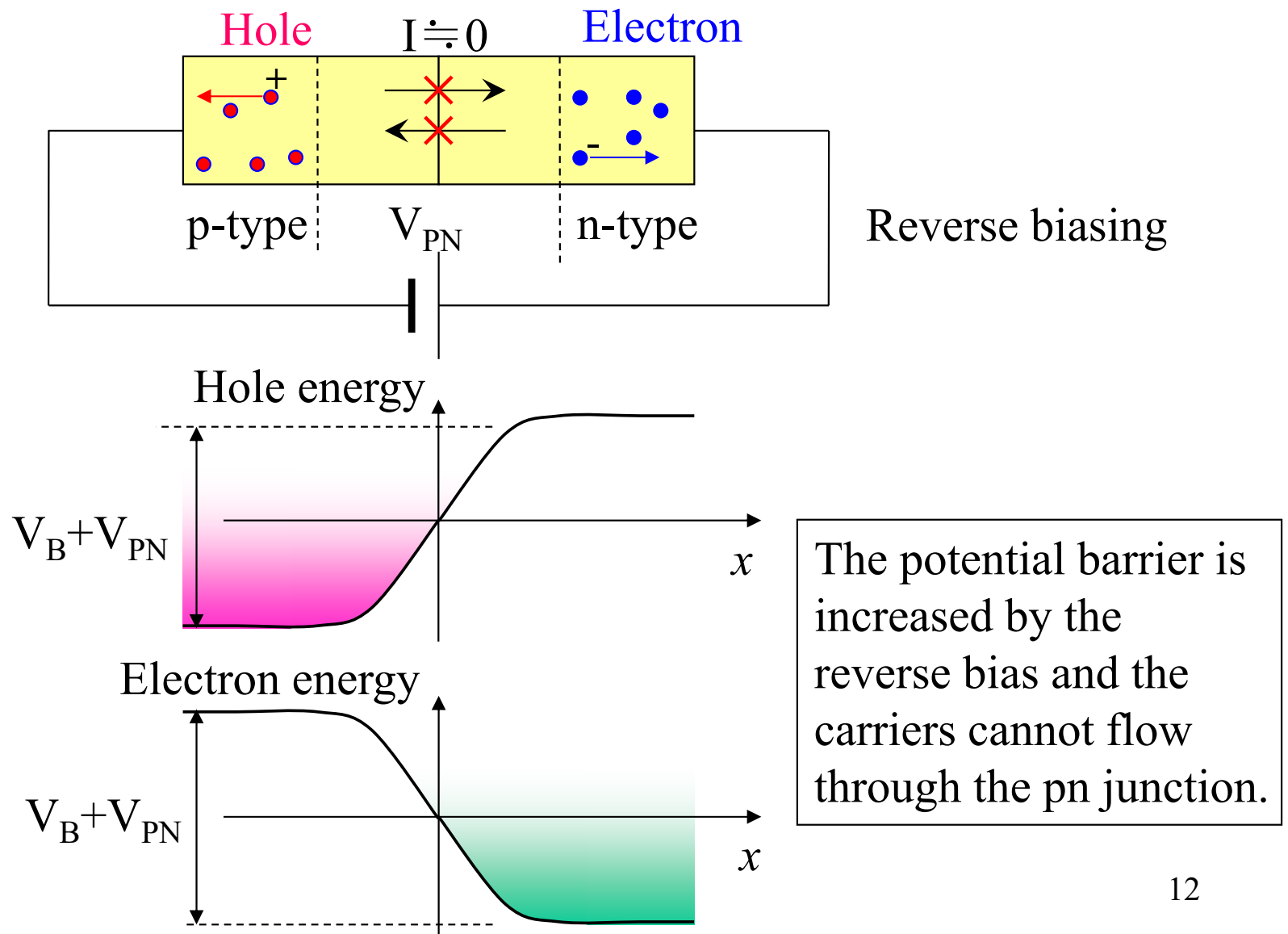
The carriers are gathered on the low-potential side.

Forward biasing of pn junction

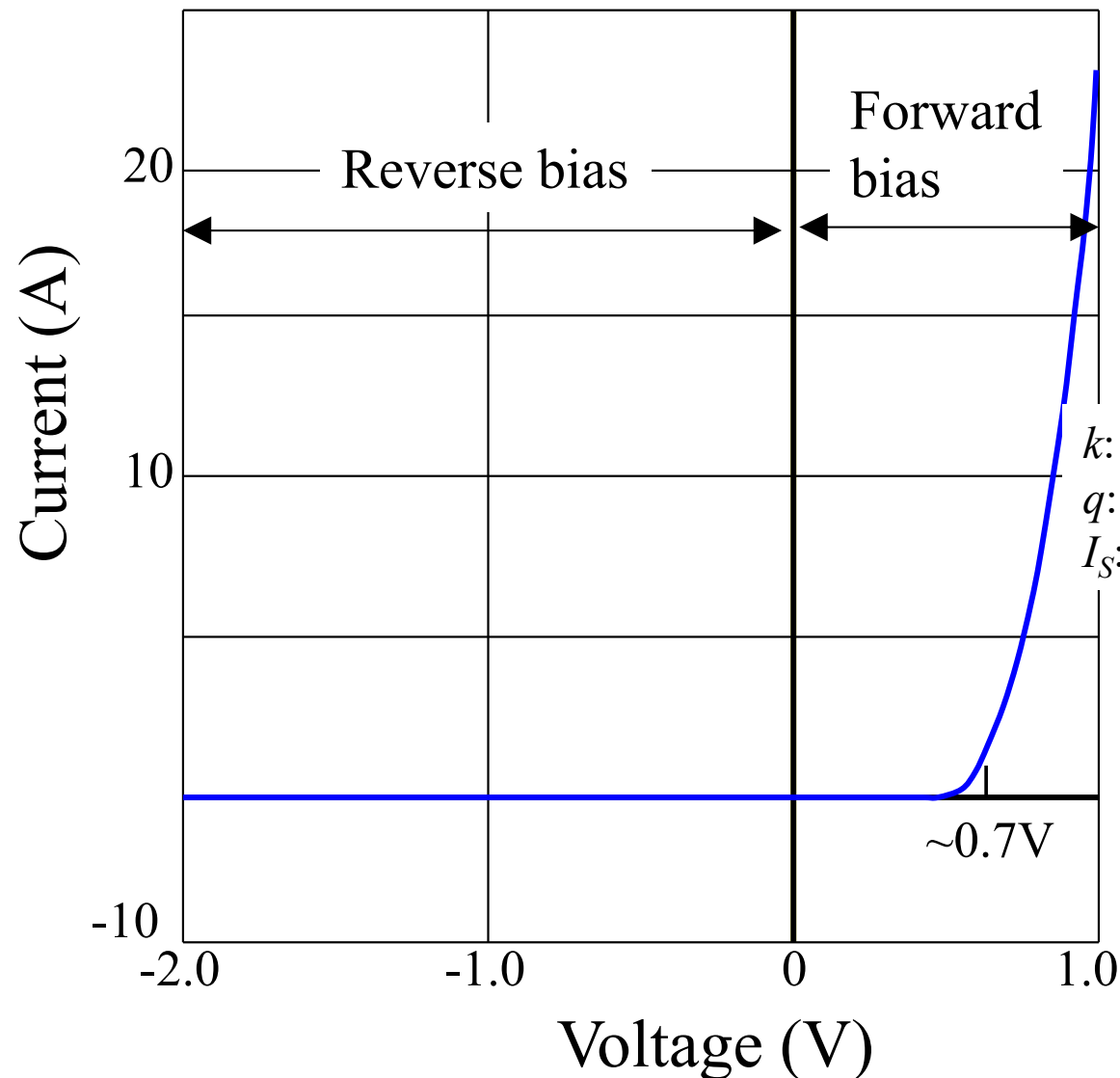


The potential barrier is decreased by the forward bias and the carriers flow through the pn junction.

Reverse biasing of pn junction



I-V characteristic of pn junction



Device model equation

$$I_{PN} = I_S \left(e^{\frac{q \cdot V_{PN}}{k \cdot T}} - 1 \right)$$

k : Boltzmann's constant ($1.380649 \cdot 10^{-23}$ J/K)

q : Electronic charge ($1.60 \cdot 10^{-19}$ coulomb)

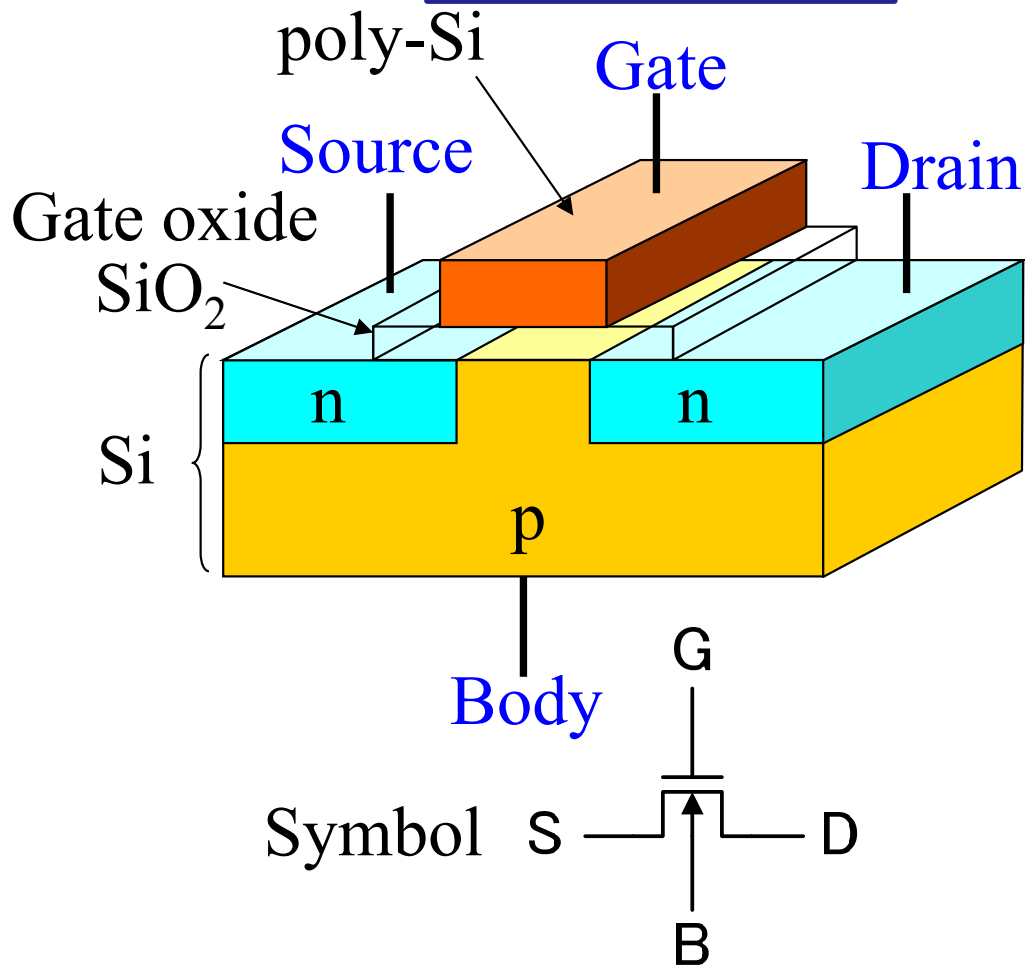
I_S : Reverse saturation current (A)

2.1.2 Structure of MOSFET

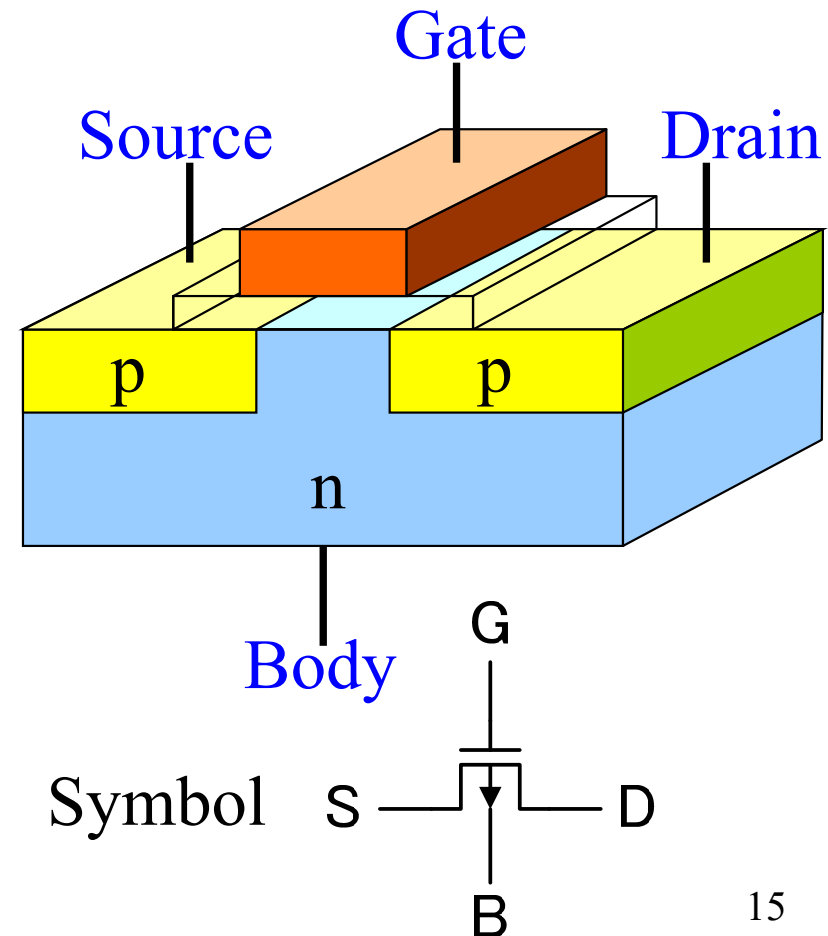
Structure of MOSFET

MOSFET (Metal-Oxide-Semiconductor Field Effect Transistor)

n-ch MOSFET

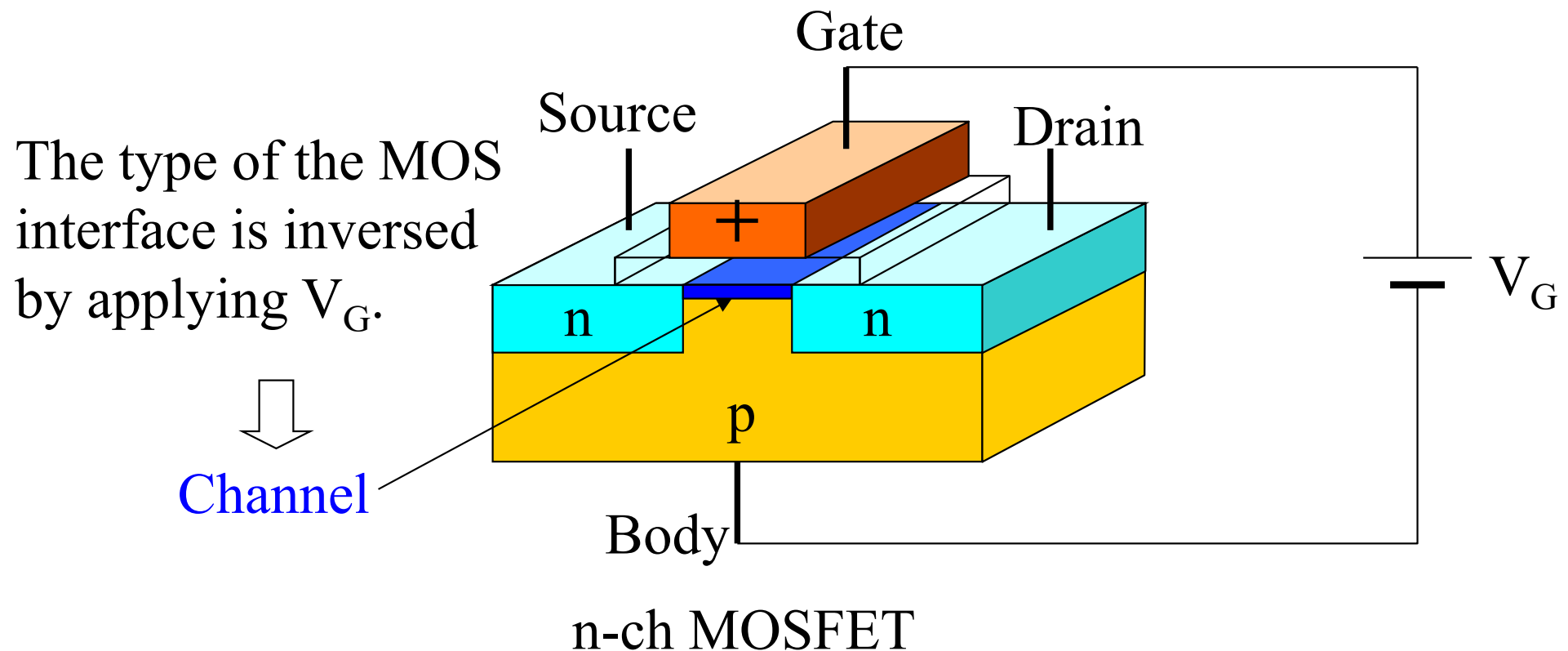


p-ch MOSFET



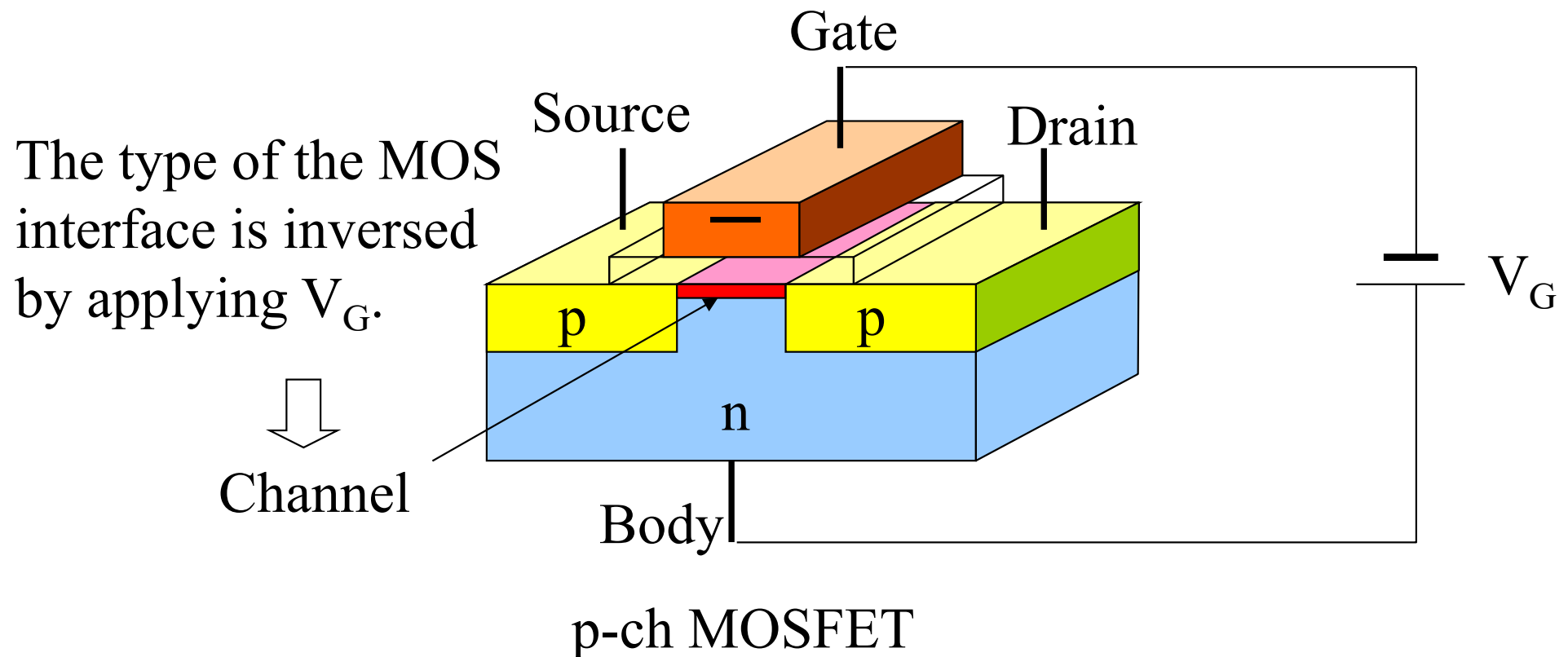
Switching of n-ch MOSFET

The free electrons are generated by lowering the potential at the SiO_2/Si interface (MOS interface) and the source and drain is electrically conducted.



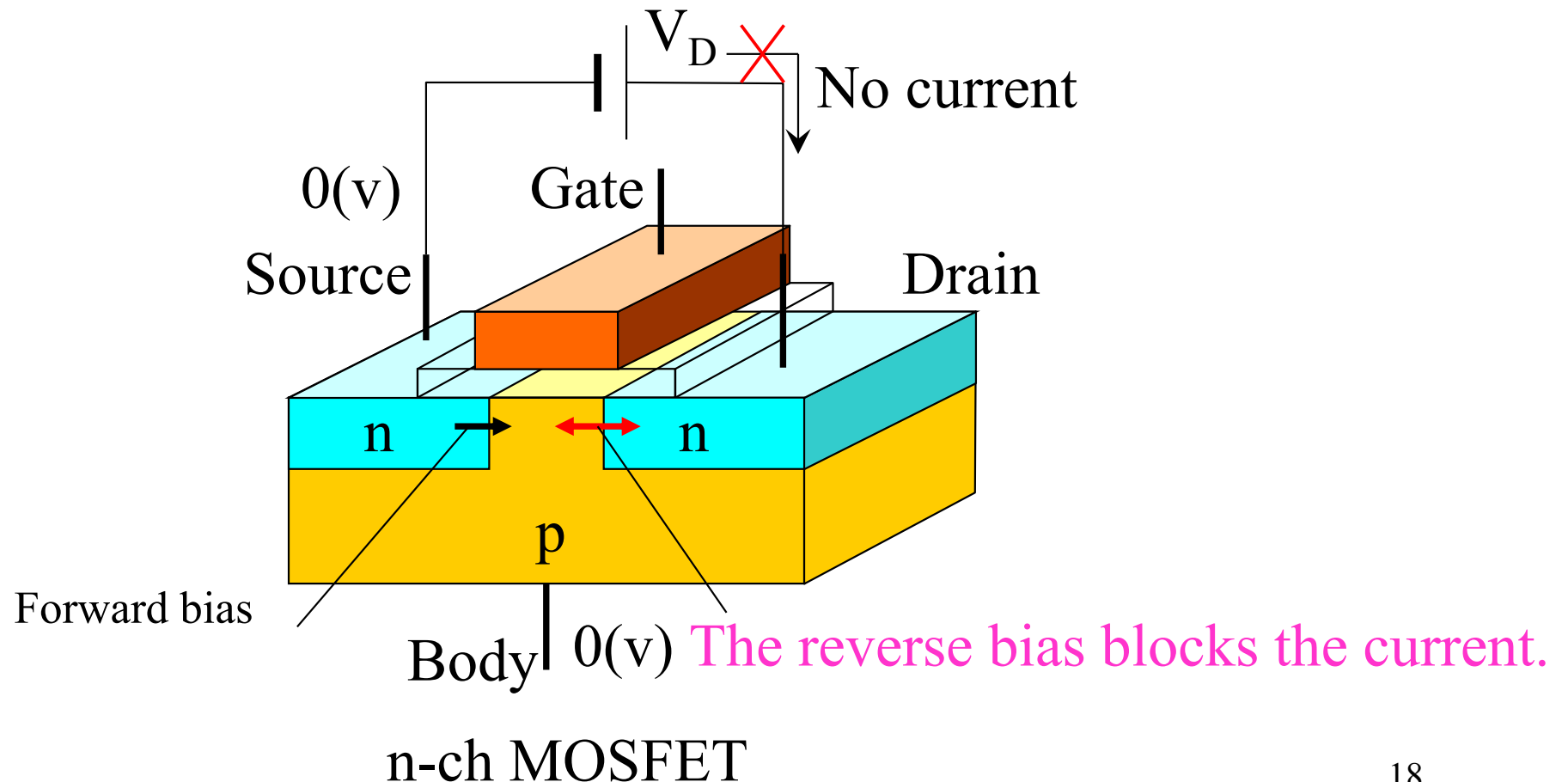
Switching of p-ch MOSFET

The holes are generated by lowering the potential at the SiO₂/Si interface (**MOS interface**) and the source and drain is electrically conducted.



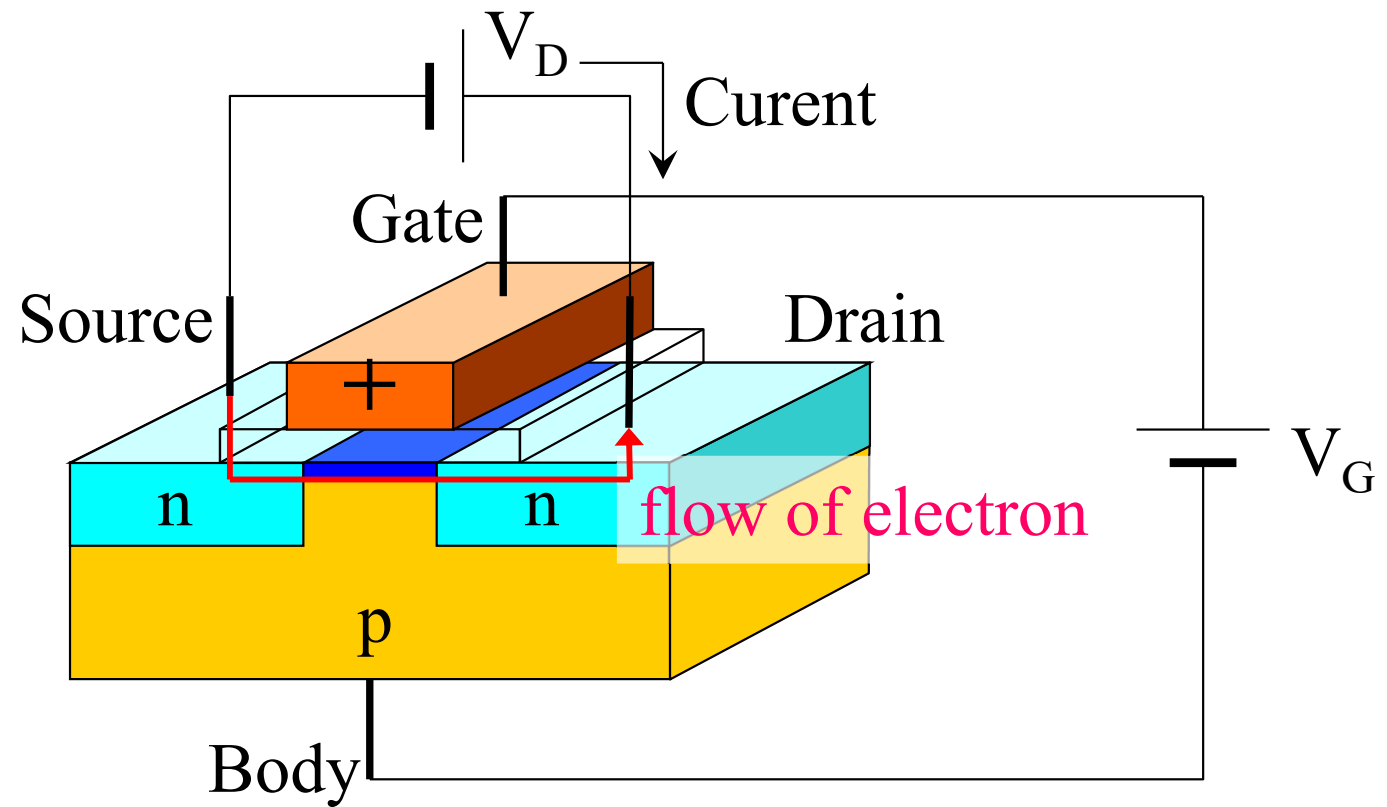
OFF state of n-ch MOSFET

The current flow is blocked by the pn junction that is reverse-biased.



ON state of n-ch MOSFET

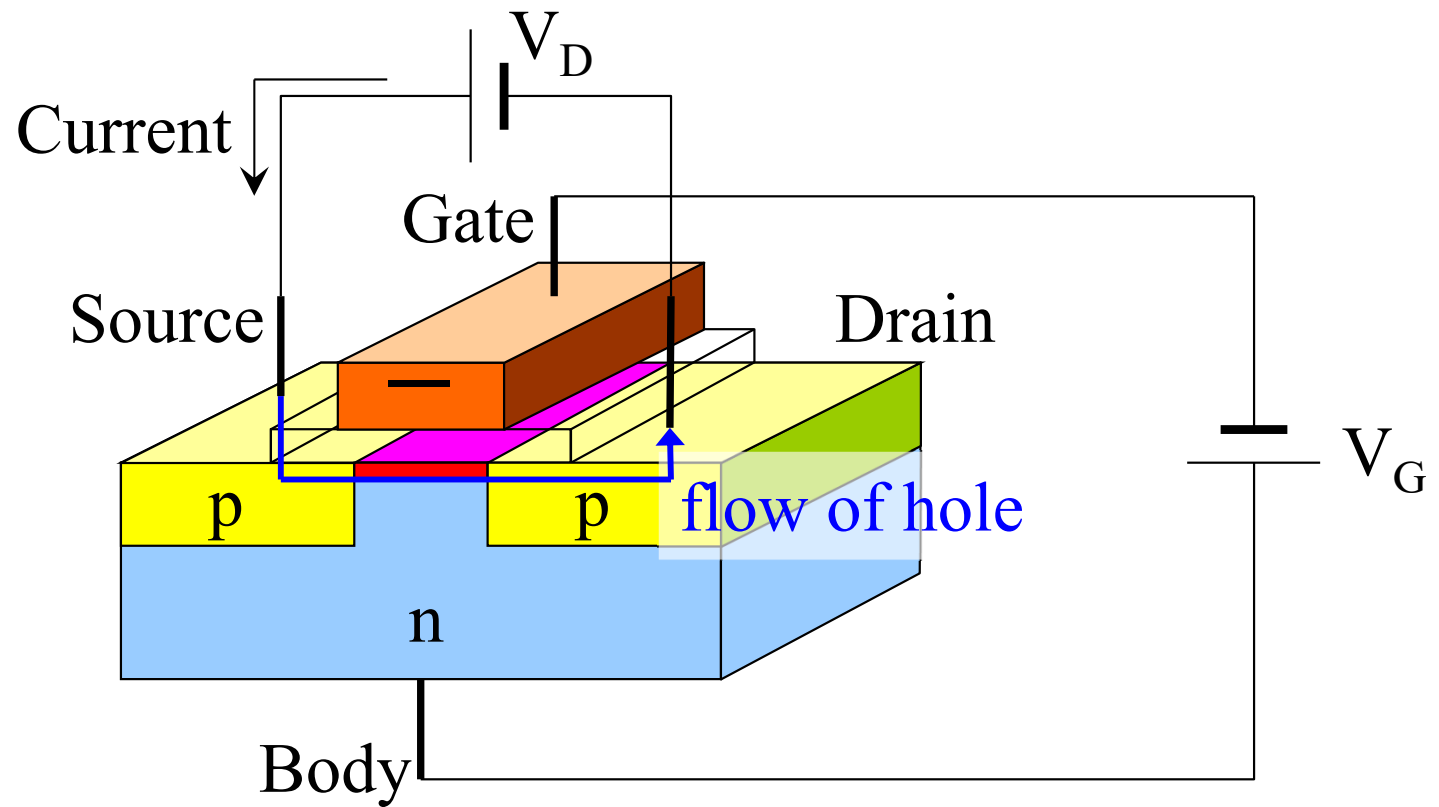
The electron flows through the channel at MOS interface.



n-ch MOSFET

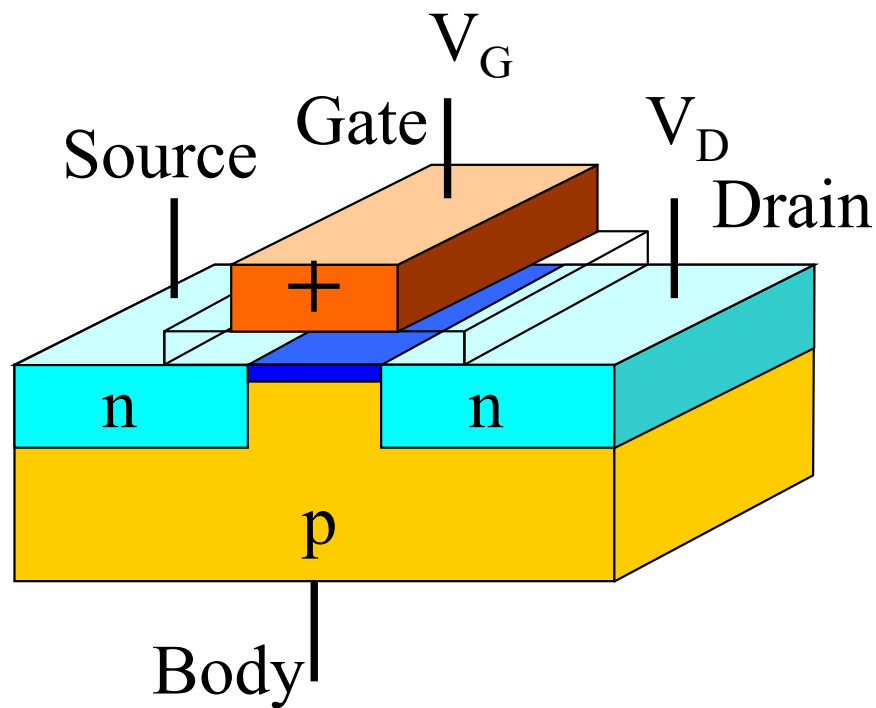
ON state of p-ch MOSFET

The hole flows through the channel at MOS interface.

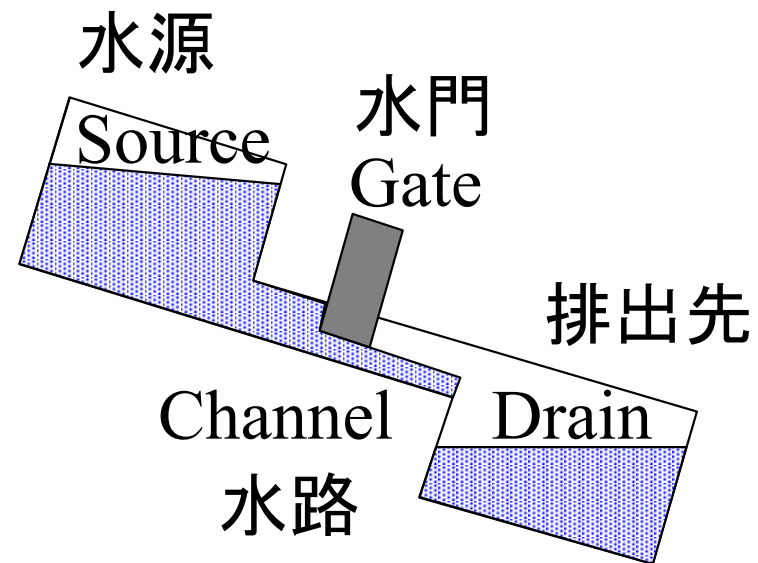


p-ch MOSFET

The origin of the electrode name



Analogy

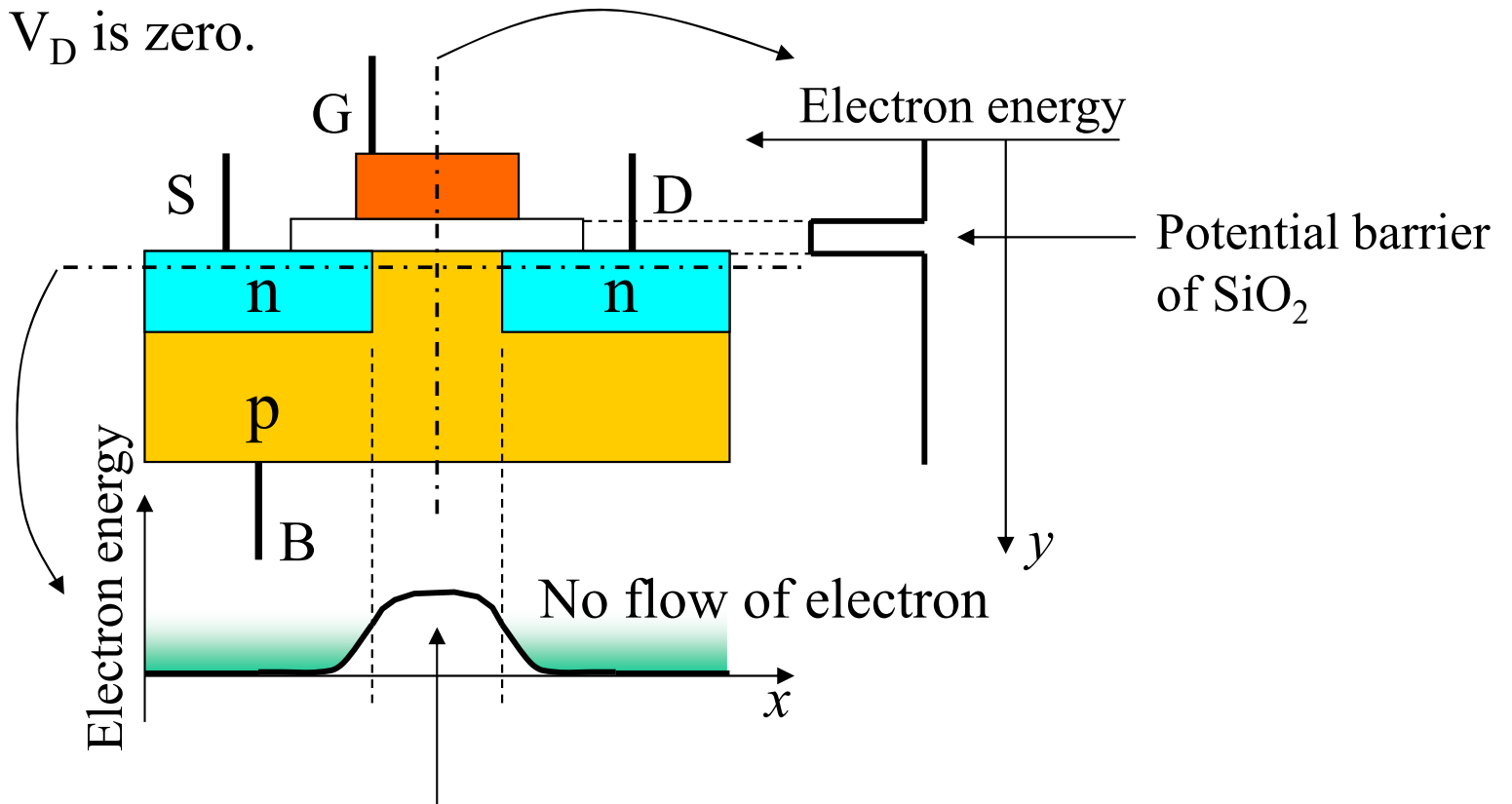


Note: Transistor = Trans-resistor

Distribution of electron in MOSFET 1

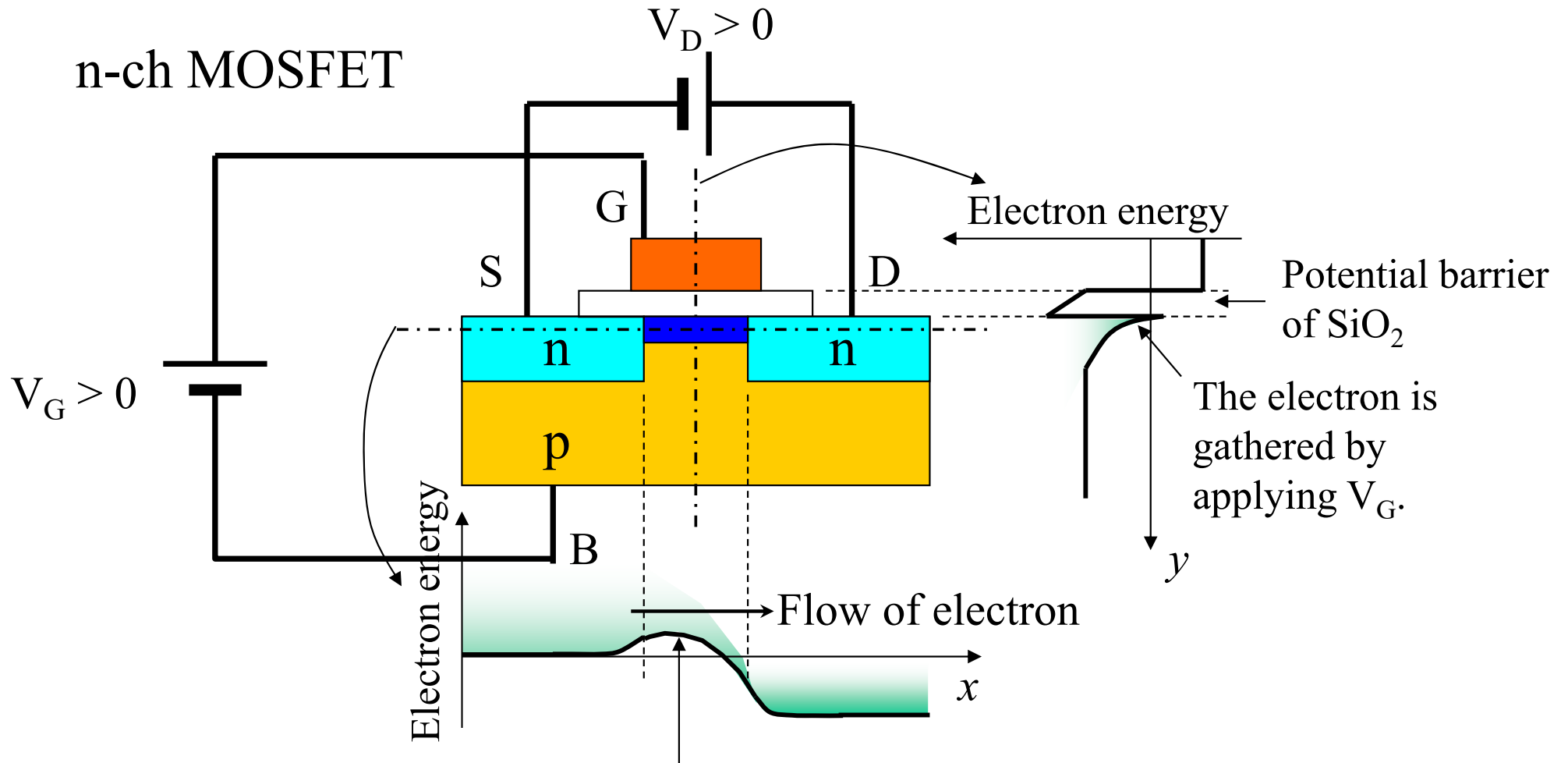
n-ch MOSFET

The V_G and the V_D is zero.



The potential barrier of p-type semiconductor is enough high and the electron cannot flow through the p-type region.

Distribution of electron in MOSFET 2



The height of the potential barrier is decreased by applying V_G and the electron flows from the source to the drain.